# **3.3 V 100/133 MHz Differential 1:8 HCSL-Compatible Push-Pull Clock ZDB/Fanout Buffer for PCIe<sup>®</sup>**

# NB3W800L

### Description

The NB3W800L is a low-power 8-output differential buffer that meets all the performance requirements of the DB800ZL specification. The NB3W800L is capable of distributing the reference clocks for Intel<sup>®</sup> QuickPath Interconnect (Intel QPI and UPI), PCIe Gen1/Gen2/Gen3/Gen4, SAS, SATA, and Intel Scalable Memory Interconnect (Intel SMI) applications. A fixed, internal feedback path maintains low drift for critical QPI applications.

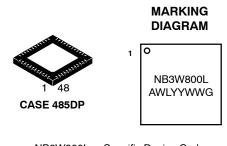
#### Features

- 8 Differential Clock Output Pairs @ 0.7 V
- Low-power NMOS Push-pull HCSL Compatible Outputs
- Cycle-to-cycle Jitter <50 ps
- Output-to-output Skew <50 ps
- Input-to-output Delay Variation <100 ps
- PCIe Phase Jitter: Gen3 <1.0 ps, Gen4 <0.5 ps RMS
- QPI 9.6GT/s 12UI Phase Jitter <0.2 ps RMS
- Pseudo-External Fixed Feedback for Lowest Input-to-Output Delay
- Individual OE Control; Hardware Control of Each Output
- PLL Configurable for PLL Mode or Bypass Mode (Fanout Operation)
- 100 MHz or 133 MHz PLL Mode Operation; Supports PCIe, QPI and UPI Applications
- Selectable PLL Bandwidth; Minimizes Jitter Peaking in Downstream PLL's
- SMBus Programmable Configurations
- Spread Spectrum Compatible; Tracks Input Clock Spreading for Low EMI
- These are Pb–Free Devices



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NB3W800L	= Specific Device Code
А	= Assembly Location
WL	= Wafer Lot
YY	= Year
WW	= Work Week
G	= Pb-Free Package

### **ORDERING INFORMATION**

Device	Package	Shipping*
NB3W800LMNG	QFN48 (Pb-Free)	490 / Tray
NB3W800LMNTXG	QFN48 (Pb-Free)	2500 / Tape & Reel

\*Pin 1 in upper left corner of Tape and Reel

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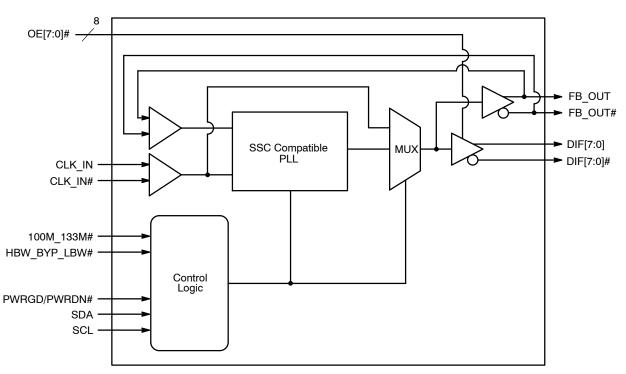


Figure 1. Simplified Block Diagram

#### Table 1. OE AND POWER PIN TABLE

Inputs		OE# Hardware Pins & Control Register Bits			Outputs	
PWRGD/ PWRDN#	CLK_IN/ CLK_IN#	SMBUS Enable Bit	OE# Pin	DIF/DIF# [7:0]	FB_OUT/ FB_OUT#	PLL State
0	х	х	Х	Hi–Z	Hi–Z	OFF
1	Running	0	Х	Hi–Z	Running	ON
		1	0	Running	Running	ON
		1	1	Hi–Z	Running	ON

### Table 2. FUNCTIONALITY AT POWER-UP (PLL MODE)

100M_133M#	CLK_IN MHz	DIF(7:0)
1	100.00	CLK_IN
0	133.33	CLK_IN

#### Table 3. POWER CONNECTIONS

Pin Number		
VDD	GND	Description
44	49	Analog PLL
3	2	Analog Input
10, 15, 19, 27, 34, 38, 42	49	DIF clocks

# Table 4. SMBus ADDRESS

Address	+ Read/Write bit
D8	R

# Table 5. PLL OPERATING MODE READBACK TABLE

HBW_BYP_LBW#	Byte0, bit 7	Byte 0, bit 6
Low (Low BW)	0	0
Mid (Bypass)	0	1
High (High BW)	1	1

#### Table 6. TRI-LEVEL INPUT THRESHOLDS

Level	Voltage
Low	<0.8 V
Mid	1.2 <vin<1.8 td="" v<=""></vin<1.8>
High	Vin > 2.2 V

# Table 7. PLL OPERATING MODE

HBW_BYP_LBW#	Mode
Low	PLL Lo BW
Mid	Bypass
High	PLL Hi BW

NOTE: PLL is OFF in Bypass Mode

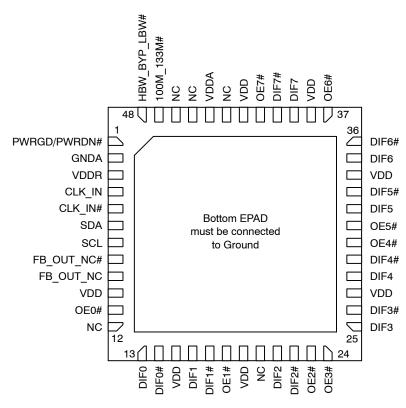


Figure 2. Pin Configuration

Table	8.	PIN	DESCRIP	TIONS

Pin #	Pin Name	Туре	Description
1	PWRGD/PWRDN#	IN	3.3 V Input notifies device to sample latched inputs and start up on first high assertion, or exit Power Down Mode on subsequent assertions. Low enters Power Down Mode.
2	GNDA	GND	Ground for Input Receiver and PLL Core
3	VDDR	PWR	3.3 V power for differential input clock (receiver). This VDD should be treated as an analog power rail and filtered appropriately.
4	CLK_IN	IN	0.7 V Differential true input
5	CLK_IN#	IN	0.7 V Differential complementary Input
6	SDA	I/O	Data pin of SMBus circuitry
7	SCL	IN	Clock pin of SMBus circuitry
8	FB_OUT_NC#	OUT	Complementary half of differential feedback output provides feedback signal to the PLL for synchronization with input clock to eliminate phase error. This pin should NOT be connected on the circuit board; the feedback is internal to the package.
9	FB_OUT_NC	OUT	True half of differential feedback output provides feedback signal to the PLL for synchronization with the input clock to eliminate phase error. This pin should NOT be connected on the circuit board; the feedback is internal to the package.
10	VDD	PWR	Power supply, nominal 3.3 V
11	OE0#	IN	Active low input for enabling DIF pair 0. This pin has an internal pull-down. 1 = disable outputs, 0 = enable outputs
12	NC	N/A	No Connection.
13	DIF0	OUT	0.7 V differential true clock output
14	DIF0#	OUT	0.7 V differential complementary clock output
15	VDD	PWR	Power supply, nominal 3.3 V
16	DIF1	OUT	0.7 V differential true clock output

#### Table 8. PIN DESCRIPTIONS

Pin #	Pin Name	Туре	Description
17	DIF1#	OUT	0.7 V differential complementary clock output
18	OE1#	IN	Active low input for enabling DIF pair 1. This pin has an internal pull-down. 1 =disable outputs, 0 = enable outputs
19	VDD	PWR	Power supply, nominal 3.3 V
20	NC	N/A	No Connection.
21	DIF2	OUT	0.7 V differential true clock output
22	DIF2#	OUT	0.7 V differential complementary clock output
23	OE2#	IN	Active low input for enabling DIF pair 2. This pin has an internal pull-down. 1 = disable outputs, 0 = enable outputs
24	OE3#	IN	Active low input for enabling DIF pair 3. This pin has an internal pull-down. 1 = disable outputs, 0 = enable outputs
25	DIF3	OUT	0.7 V differential true clock output
26	DIF3#	OUT	0.7 V differential complementary clock output
27	VDD	PWR	Power supply, nominal 3.3 V
28	DIF4	OUT	0.7 V differential true clock output
29	DIF4#	OUT	0.7 V differential complementary clock output
30	OE4#	IN	Active low input for enabling DIF pair 4. This pin has an internal pull-down. 1 = disable outputs, 0 = enable outputs
31	OE5#	IN	Active low input for enabling DIF pair 5. This pin has an internal pull-down. 1 =disable outputs, 0 = enable outputs
32	DIF5	OUT	0.7 V differential true clock output
33	DIF5#	OUT	0.7 V differential complementary clock output
34	VDD	PWR	Power supply, nominal 3.3 V
35	DIF6	OUT	0.7 V differential true clock output
36	DIF6#	OUT	0.7 V differential complementary clock output
37	OE6#	IN	Active low input for enabling DIF pair 6. This pin has an internal pull-down. 1 = disable outputs, 0 = enable outputs
38	VDD	PWR	Power supply, nominal 3.3 V
39	DIF7	OUT	0.7 V differential true clock output
40	DIF7#	OUT	0.7 V differential complementary clock output
41	OE7#	IN	Active low input for enabling DIF pair 7. This pin has an internal pull-down. 1 = disable outputs, 0 = enable outputs
42	VDD	PWR	Power supply, nominal 3.3 V
43	NC	N/A	No Connection.
44	VDDA	PWR	3.3 V power for the PLL core.
45	NC	N/A	No Connection.
46	NC	N/A	No Connection.
47	100M_133M#	IN	3.3 V Input to select operating frequency. See Functionality Table for Definition
48	HBW_BYP_LBW#	IN	Trilevel input to select High BW, Bypass or Low BW mode. See PLL Operating Mode Table for Details.
49	GND	PWR	EPAD, must be connected to Ground

#### **Table 9. ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Conditions	Min	Тур	Max	Units
VDD, VDDA	3.3 V Supply Voltage (Notes 1, 2)	VDD for core logic and PLL			4.6	V
V <sub>IL</sub>	Input Low Voltage (Note 1)		GND-0.5			V
V <sub>IH</sub>	Input High Voltage (Note 1)	Except for SMBus interface			V <sub>DD</sub> + 0.5	V
V <sub>IHSMB</sub>	Input High Voltage (Note 1)	SMBus clock and data pins			5.5	V
Ts	Storage Temperature (Note 1)		-65		150	°C
Tj	Junction Temperature (Note 1)				125	°C
ESD prot	Input ESD protection (Note 1)	Human Body Model	2000			V
$\theta_{JA}$	Thermal Resistance, Junction-to-Ambient	Still air		17		°C/W
$\theta_{\text{JC}}$	Thermal Resistance, Junction-to-Case			7		°C/W

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Guaranteed by design and characterization, not tested in production.

2. Operation under these conditions is neither implied nor guaranteed.

# Table 10. ELECTRICAL CHARACTERISTICS-CLOCK INPUT PARAMETERS (HCSL-COMPATIBLE) $(V_{DD} = V_{DDA} = 3.3 V \pm 5\%, T_A = 0^{\circ}C - 70^{\circ}C)$ , See Test Loads for Loading Conditions. (Note 5)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
V <sub>IHCLK_IN</sub>	Input High Voltage - CLK_IN (Note 3)	Differential inputs (single-ended measurement)	600	800	1150	mV
VILCLK_IN	Input Low Voltage - CLK_IN (Note 3)	Differential inputs (single-ended measurement)	V <sub>SS</sub> - 300	0	300	mV
V <sub>COM</sub>	Input Common Mode Voltage - CLK_IN (Note 3)	Common Mode Input Voltage (Single-ended measurement)	300		1000	mV
V <sub>SWING</sub>	Input Amplitude - CLK_IN (Note 3)	Peak to Peak (differential)	300		1450	mV
dv/dt	Input Slew Rate - CLK_IN (Notes 3, 4)	Measured differentially	0.35		8	V/ns
I <sub>IN</sub>	Input Leakage Current (Note 3)	$V_{IN} = V_{DD}$ , $V_{IN} = GND$	-5		5	μA
d <sub>tin</sub>	Input Duty Cycle (Note 3)	Measurement from differential waveform	45		55	%
J <sub>DIFIn</sub>	Input Jitter - Cycle to Cycle (Note 3)	Differential Measurement			125	ps

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Guaranteed by design and characterization, not tested in production.

4. Slew rate measured through ±75 mV window centered around differential zero.

5. Test configuration is; Rs = 27  $\Omega$ , 2 pF for 85  $\Omega$  transmission line.

# Table 11. ELECTRICAL CHARACTERISTICS – Input/Supply/Common Parameters $(V_{DD} = V_{DDA} = 3.3 \text{ V} \pm 5\%, T_A = 0^{\circ}\text{C} - 70^{\circ}\text{C})$ , See Test Loads for Loading Conditions. (Note 11)

Symbol	Parameter	Conditions	Min	Тур	Мах	Units
V <sub>IH</sub>	Input High Voltage (Note 6) Single-ended inputs, except S low threshold and tri-level in		2		V <sub>DD</sub> + 0.3	V
V <sub>IL</sub>	Input Low Voltage (Note 6)	Single-ended inputs, except SMBus, low threshold and tri-level inputs	GND – 0.3		0.8	V
I <sub>IN</sub>	Input Current (Note 6)	Single–ended inputs, V <sub>IN</sub> = GND, V <sub>IN</sub> = V <sub>DD</sub>	-5		5	μA
I <sub>INP</sub>		Single-ended inputs V <sub>IN</sub> = 0 V; Inputs with internal pull-up resistors V <sub>IN</sub> = V <sub>DD</sub> ; Inputs with internal pull-down resistors	-200		200	μΑ
F <sub>ibyp</sub>	Input Frequency (Note 7)	$V_{DD}$ = 3.3 V, Bypass mode	33		150	MHz
F <sub>ipll</sub>	]	$V_{DD}$ = 3.3 V, 100 MHz PLL mode	99	100.00	101	MHz
F <sub>ipll</sub>	]	V <sub>DD</sub> = 3.3 V, 133.33 MHz PLL mode	132.33	133.33	134.33	MHz
L <sub>pin</sub>	Pin Inductance (Note 6)				7	nH
C <sub>IN</sub>	Capacitance (Note 6)	Logic Inputs, except CLK_IN	1.5		4.5	pF
C <sub>INCLK_IN</sub>	]	CLK_INdifferential clock inputs (Note 9)	1.5		2.7	pF
C <sub>OUT</sub>	]	Output pin capacitance			4.5	pF
f <sub>MODIN</sub>	Input SS Modulation Frequency (Note 6)	Allowable Frequency (Triangular Modulation)	30		33	kHz
t <sub>LATOE</sub> #	OE# Latency (Notes 6. 8)	DIF start after OE# assertion DIF stop after OE# deassertion	4		8	cycles
t <sub>DRVPD</sub>	Tdrive_PD# (Notes 6, 8)	DIF output enable after PD# de-assertion			300	μs
t <sub>F</sub>	Tfall (Notes 6, 7)	Fall time of control inputs			10	ns
t <sub>R</sub>	Trise (Notes 6, 7)	Rise time of control inputs			10	ns
V <sub>ILSMB</sub>	SMBus Input Low Voltage (Note 6)				0.8	V
V <sub>IHSMB</sub>	SMBus Input High Voltage (Note 6)		2.1		V <sub>DDSMB</sub>	V
V <sub>OLSMB</sub>	SMBus Output Low Voltage (Note 6)	@ I <sub>PULLUP</sub>			0.4	V
I <sub>PULLUP</sub>	SMBus Sink Current (Note 6)	@ V <sub>OL</sub>	4			mA
V <sub>DDSMB</sub>	Nominal Bus Voltage (Note 6)	3 V to 5 V ±10%	2.7		5.0	V
t <sub>RSMB</sub>	SCL/SDA Rise Time (Note 6)	(Max V <sub>IL</sub> - 0.15) to (Min V <sub>IH</sub> + 0.15)			1000	ns
t <sub>FSMB</sub>	SCL/SDA Fall Time (Note 6)	(Min V <sub>IH</sub> + 0.15) to (Max V <sub>IL</sub> - 0.15)			300	ns
f <sub>MAXSMB</sub>	SMBus Operating Frequency (Notes 6, 10)	Maximum SMBus operating frequency			100	kHz

Guaranteed by design and characterization, not tested in production.
 Control input must be monotonic from 20% to 80% of input swing.

8. Time from deassertion until outputs are >200 mV

9. CLK\_IN input 10. The differential input clock must be running for the SMBus to be active 11. Test configuration is; Rs =  $27 \Omega$ , 2 pF for 85  $\Omega$  transmission line.

Table 12. DIF 0.7 V AC TIMING CHARACTERISTICS (Non-Spread or -0.5% Spread Spectrum Mode)
$(V_{DD} = V_{DDA} = 3.3 V \pm 5\%, T_A = 0^{\circ}C - 70^{\circ}C)$ , See Test Loads for Loading Conditions.

			CLK = 100 MHz, 133.33 MHz		
Symbol	Para	meter	Min	Мах	Unit
Tstab (Note 32)	Clock Stabi	Clock Stabilization Time		1.8	ms
Laccuracy (Notes 15, 19, 27, 33)	Long A	ccuracy		100	ppm
Tabs (Notes 15, 16, 19)	Absolute	No Spread	9.94900 for 100 MHz	10.05100 for 100 MHz	ns
	Min/Max Host CLK		7.44925 for 133 MHz	7.55075 for 133 MHz	
	Period	-0.5% Spread	9.49900 for 100 MHz	10.10126 for 100 MHz	
			7.44925 for 133 MHz	7.58845 for 133 MHz	
Slew_rate (Notes 13, 15, 19)	DIFF OUT	Slew_rate	1.0	4.0	V/ns
$\Delta$ Trise / $\Delta$ Tfall (Notes 15, 19, 29)	Rise and Fall	Rise and Fall Time Variation		125	ps
Rise/Fall Matching (Notes 15, 19, 30, 31)				20	%
VHigh (Notes 15, 18, 21)	Voltage High	(typ 0.70 Volts)	660	850	mV
VLow (Notes 15, 18, 22)	Voltage Low	(typ 0.0 Volts)	-150	150	mV
Vmax (Note 18)	Maximur	n Voltage		1150	mV
Vcross absolute (Notes 12, 14, 15, 18, 25)	Absolute Crossir	ng Point Voltages	250	550	mV
Vcross relative (Notes 15, 17, 18, 25)	Relative Crossir	ng Point Voltages	Calc	Calc	
Total $\Delta$ Vcross (Notes 15, 18, 26)	Total Variation of Vcross Over All Edges			140	mV
Vovs (Notes 15, 18, 23)	Maximum Volta	age (Overshoot)		Vhigh + 0.3	V
Vuds (Notes 15, 18, 24)	Maximum Volta	ge (Undershoot)		Vlow – 0.3	V

12. Measured at crossing point where the instantaneous voltage value of the rising edge of CLK equals the falling edge of CLK#.

13. Measurment taken from differential waveform on a component test board. The slew rate is measured from –150 mV to +150 mV on the differential waveform. Scope is set to average because the scope sample clock is making most of the dynamic wiggles along the clock edge Only valid for Rising CLK IN and Falling CLK IN#. Signal must be monotonic through the Vol to Voh region for Trise and Tfall.

14. This measurement refers to the total variation from the lowest crossing point to the highest, regardless of which edge is crossing.

15. Test configuration is; Rs = 27  $\Omega$ , 2 pF for 85  $\Omega$  transmission line.

16. The average period over any 1 µs period of time must be greater than the minimum and less than the maximum specified period.

17. Vcross(rel) Min and Max are derived using the following, Vcross(rel) Min = 0.250 + 0.5 (Vhavg – 0.700), Vcross(rel) Max = 0.550 – 0.5 (0.700 – Vhavg)

18. Measurement taken from Single Ended waveform.

19. Measurement taken from differential waveform. Bypass mode, input duty cycle = 50%.

20. Unless otherwise noted, all specifications in this table apply to all processor frequencies.

21. VHigh is defined as the statistical average High value as obtained by using the Oscilloscope VHigh Math function.

22. VLow is defined as the statistical average Low value as obtained by using the Oscilloscope VLow Math function.

23. Overshoot is defined as the absolute value of the maximum voltage.

24. Undershoot is defined as the absolute value of the minimum voltage.

25. The crossing point must meet the absolute and relative crossing point specifications simultaneously.

26. ΔVcross is defined as the total variation of all crossing voltages of Rising DIF and Falling DIF#. This is the maximum allowed variance in Vcross for any particular system.

27. Using frequency counter with the measurement interval equal or greater than 0.15 s, target frequencies are 100,000,000 Hz, 133,333,333 Hz.

28. Using frequency counter with the measurement interval equal or greater than 0.15 s, target frequencies are 99,750,00 Hz, 133,000,000 Hz.

29. Measured with oscilloscope, averaging off, using min max statistics. Variation is the delta between min and max.

30. Measured with oscilloscope, averaging on, The difference between the rising edge rate (average) of DIF versus the falling edge rate (average) of DIF#. Measured in a ±75 mV window around the crosspoint of DIF and DIF#.

31. Rise/Fall matching is derived using the following, 2\*(Trise - Tfall) / (Trise + Tfall).

32. This is the time from the valid CLK\_IN input clocks and the assertion of the PWRGD signal level at 1.8 V – 2.0 V to the time that stable clocks are output from the buffer chip (PLL locked).

33. All Long Term Accuracy specifications are guaranteed with the assumption that the input clock complies with CK410B+/CK420BQ accuracy requirements. The NB3W800L itself does not contribute to ppm error.

#### Table 13. ELECTRICAL CHARACTERISTICS – Current Consumption

 $(V_{DD} = V_{DDA} = 3.3 \text{ V} \pm 5\%, T_A = 0^{\circ}\text{C} - 70^{\circ}\text{C})$ , See Test Loads for Loading Conditions. (Note 35)

Symbol	Parameter	Conditions	Min	Тур	Мах	Units
I <sub>DDVDD</sub>	Operating Current (Note 34)	133 MHz, VDD rail		94	105	mA
I <sub>DDVDDA</sub>		133 MHz, VDDA + VDDR rail, PLL Mode		38	50	mA
IDDVDDPD	Powerdown Current (Note 34)	Power Down, VDD Rail		2.0	3.5	mA
IDDVDDAPD		Power Down, VDDA Rail		0.5	1.0	mA

34. Guaranteed by design and characterization, not tested in production.

35. C<sub>L</sub> = 2 pF with RS = 27  $\Omega$  for Zo = 85  $\Omega$  differential trace impedance.

#### Table 14. ELECTRICAL CHARACTERISTICS – Skew and Differential Jitter Parameters

(V<sub>DD</sub> = V<sub>DDA</sub> = 3.3 V  $\pm$ 5%, T<sub>A</sub> = 0°C – 70°C), See Test Loads for Loading Conditions.

Symbol	Parameter	Conditions	Min	Тур	Мах	Units
t <sub>SPO_PLL</sub>	CLK_IN, DIF[x:0] (Notes 36, 37, 39, 40, 43)	Input-to-Output Skew in PLL mode nominal value @ 25°C, 3.3 V	-100		100	ps
t <sub>PD_BYP</sub>	CLK_IN, DIF[x:0] (Notes 36, 37, 39, 40, 43)	Input-to-Output Skew in Bypass mode nominal value @ 25°C, 3.3 V	2.5		4.5	ns
t <sub>DSPO_PLL</sub>	CLK_IN, DIF[x:0] (Notes 36, 37, 39, 40, 43)	Input-to-Output Skew Varation in PLL mode across voltage and temperature	-100		100	ps
t <sub>DSPO_BYP</sub>	CLK_IN, DIF[x:0] (Notes 36, 37, 39, 40, 43)	Input-to-Output Skew Varation in Bypass mode across voltage and temperature	-250		250	ps
t <sub>SKEW_ALL</sub>	DIF{x:0] (Notes 36, 37, 39, 43)	Output-to-Output Skew across all outputs (Common to Bypass and PLL mode)			50	ps
jpeak-hbw	PLL Jitter Peaking (Notes 36, 42, 43)	HBW_BYP_LBW# = 1			2.5	dB
jpeak-lbw	PLL Jitter Peaking (Notes 36, 42, 43)	HBW_BYP_LBW# = 0			2	dB
pll <sub>HBW</sub>	PLL Bandwidth (Notes 36, 43, 44)	HBW_BYP_LBW# = 1	2	3	4	MHz
pll <sub>LBW</sub>	PLL Bandwidth (Notes 36, 43, 44)	HBW_BYP_LBW# = 0	0.7	1	1.4	MHz
t <sub>DC</sub>	Duty Cycle (Note 36, 46)	Measured differentially, PLL and Bypass Mode	45	50	55	%
tDCD	Duty Cycle Distortion (Notes 36, 45)	Measured differentially, Bypass Mode @ 100 MHz	-2	0	2	%
t <sub>jcyc-cyc</sub>	Jitter, Cycle to cycle	PLL mode			50	ps
	(Notes 36, 46)	Additive Jitter in Bypass Mode			50	ps

36. C<sub>L</sub> = 2 pF with RS = 27 Ω for Zo = 85 Ω differential trace impedance. Input to output skew is measured at the first output edge following the corresponding input.

37. Measured from differential cross-point to differential cross-point. This parameter can be tuned with external feedback path, if present.

38. All Bypass Mode Input-to-Output specs refer to the timing between an input edge and the specific output edge created by it. 39. This parameter is deterministic for a given device

40. Measured with scope averaging on to find mean value.

41.t is the period of the input clock

42. Measured as maximum pass band gain. At frequencies within the loop BW, highest point of magnification is called PLL jitter peaking.

43. Guaranteed by design and characterization, not tested in production.

44. Measured at 3 db down or half power point.

45. Duty cycle distortion is the difference in duty cycle between the output and the input clock when the device is operated in bypass mode. 46. Measured from differential waveform. Bypass mode, input duty cycle = 50%.

#### Table 15. ELECTRICAL CHARACTERISTICS – PHASE JITTER PARAMETERS

 $(V_{DD} = V_{DDA} = 3.3 \text{ V} \pm 5\%, \text{ TA} = 0^{\circ}\text{C} - 70^{\circ}\text{C})$ , See Test Loads for Loading Conditions. (Note 35)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
t <sub>jphPCleG1</sub>		PCIe Gen 1 (Notes 48, 49)		13	86	ps (p–p)
t <sub>jph</sub> PCleG2		PCIe Gen 2 Lo Band 10 kHz < f < 1.5 MHz (Note 48)		0.25	3.0	ps (rms)
		PCIe Gen 2 High Band 1.5 MHz < f < Nyquist (50 MHz) (Note 48)		1.05	3.1	ps (rms)
t <sub>jphPCleG3</sub>		PCIe Gen 3 (PLL BW of 2–4 MHz, CDR = 10 MHz) (Notes 48, 50)		0.21	1.0	ps (rms)
t <sub>jphPCleG4</sub>	Phase Jitter, PLL Mode (Note 47)	PCIe Gen 4 (PLL BW of 2–4 MHz, CDR = 10 MHz) (Notes 48, 50)		0.21	0.5	ps (rms)
t <sub>jphUPI</sub>		UPI (9.6 Gb/s, 10.4 Gb/s or 11.2 Gb/s, 100 MHz, 12 UI)		0.7	1.0	ps (rms)
t <sub>jphQPI_SMI</sub>		QPI & SMI (100 MHz or 133 MHz, 4.8 Gb/s, 6.4 Gb/s 12 UI) (Note 51)		0.14	0.5	ps (rms)
		QPI & SMI (100 MHz, 8.0 Gb/s, 12 UI) (Note 51)		0.1	0.3	ps (rms)
		QPI & SMI (100 MHz, 9.6 Gb/s, 12 UI) (Note 51)		0.08	0.2	ps (rms)
t <sub>jphPCleG1</sub>		PCIe Gen 1 (Notes 48, 49)			10	ps (p–p)
t <sub>jphPCleG2</sub>		PCIe Gen 2 Lo Band 10 kHz < f < 1.5 MHz (Notes 48, 52)			0.3	ps (rms)
		PCle Gen 2 High Band 1.5 MHz < f < Nyquist (50 MHz) (Notes 48, 52)			0.6	ps (rms)
t <sub>jphPCleG3</sub>	Additive Phase Jitter, Bypass mode	PCIe Gen 3 (PLL BW of 2–4 MHz, 2–5 MHz, CDR = 10 MHz) (Notes 48, 50, 52)			0.2	ps (rms)
t <sub>jphQPI_SMI</sub>	(Note 47)	QPI & SMI (100 MHz or 133 MHz, 4.8 Gb/s, 6.4 Gb/s 12 UI) (Notes 51, 52)			0.2	ps (rms)
		QPI & SMI (100 MHz, 8.0 Gb/s, 12 UI) (Notes 51, 52)			0.1	ps (rms)
		QPI & SMI (100 MHz, 9.6 Gb/s, 12 UI) (Notes 51, 52)			0.1	ps (rms)

47. Applies to all outputs.
48. See http://www.pcisig.com for complete specs
49. Sample size of at least 100K cycles. This figures extrapolates to 108ps pk-pk @ 1M cycles for a BER of 1–12.
50. Subject to final ratification by PCI SIG.
51. Calculated from Intel-supplied Clock Jitter Tool v 1.6.3
52. For RMS figures, additive jitter is calculated by solving the following equation: (Additive jitter)<sup>2</sup> = (total jittter)<sup>2</sup> - (input jitter)<sup>2</sup>

### Table 16. CLOCK PERIODS – Differential Outputs with Spread Spectrum Disabled

				Mea	surement W	índow			
		1 Clock	1 μs	0.1 s	0.1 s	0.1 s	1 μs	1 Clock	
SSC OFF	Center Freq. MHz	-c2c Jitter Abs Per Min	–SSC Short–Term Average Min	– ppm Long–Term Average Min	0 ppm Period Nominal	+ ppm Long-Term Average Max	+SSC Short-Term Average Max	+c2c Jitter Abs Per Max	Units
DIF (Notes 53, 54, 55)	100.00	9.94900		9.99900	10.00000	10.00100		10.05100	ns
DIF (Notes 53, 54, 56)	133.33	7.44925		7.49925	7.50000	7.50075		7.55075	ns

#### Table 17. CLOCK PERIODS – Differential Outputs with Spread Spectrum Enabled

		Measurement Window							
		1 Clock	1 μs	0.1 s	0.1 s	0.1 s	1 μs	1 Clock	
SSC ON	Center Freq. MHz	-c2c Jitter Abs Per Min	–SSC Short–Term Average Min	– ppm Long–Term Average Min	0 ppm Period Nominal	+ ppm Long-Term Average Max	+SSC Short-Term Average Max	+c2c Jitter Abs Per Max	Units
DIF (Notes 53, 54, 55)	99.75	9.94906	9.99906	10.02406	10.02506	10.02607	10.05107	10.10107	ns
DIF (Notes 53, 54, 56)	133.00	7.44930	7.49930	7.51805	7.51880	7.51955	7.53830	7.58830	ns

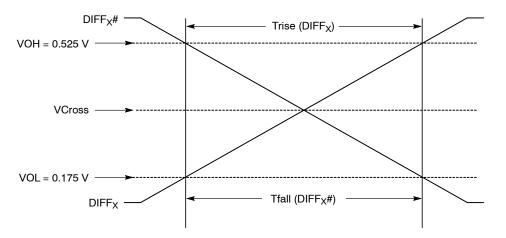
53. Guaranteed by design and characterization, not tested in production.

54. All Long Term Accuracy specifications are guaranteed with the assumption that the input clock complies with CK420BQ/CK410B+ accuracy requirements (±100 ppm). The device itself does not contribute to ppm error.

55. Driven by SRC output of main clock, 100 MHz PLL Mode or Bypass mode

56. Driven by CPU output of main clock, 133 MHz PLL Mode or Bypass mode

# **Measurement Points for Differential**



#### Figure 3. Single-Ended Measurement Points for Trise, Tfall

#### **Measurement Points for Differential**

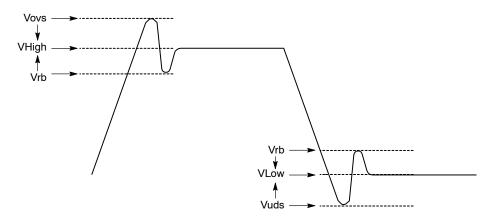


Figure 4. Single-Ended Measurement Points for Vovs, Vuds, Vrb

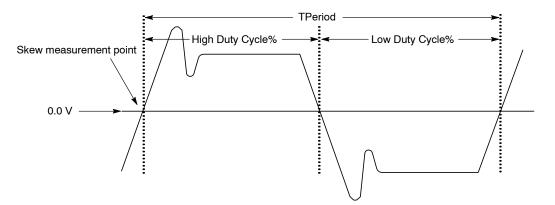
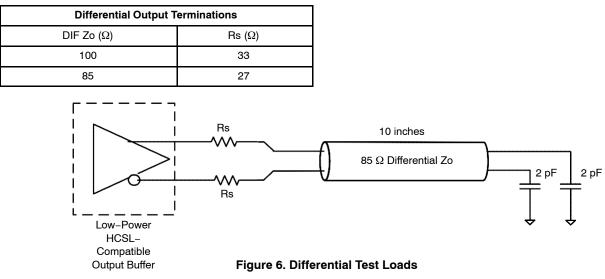


Figure 5. Differential (DIFF<sub>X</sub> – DIFF<sub>X</sub>#) Measurement Points (Tperiod, Duty Cycle, Jitter)

Test Loads



#### SIGNAL AND FEATURE OPERATION

#### CLK\_IN, CLK\_IN#

The differential input clock is expected to be sourced from a clock synthesizer with an HCSL–compatible output, e.g. CK420BQ, CK–NET, CK–uS, or CK509B or another driver.

#### **OE# and Output Enables (Control Registers)**

Each output can be individually enabled or disabled by SMBus control register bits. Additionally, each output of the DIF[7:0] has a dedicated OE# pin. The OE# pins are asynchronous asserted–low signals. The Output Enable bits in the SMBus registers are active high and are set to enable by default.

The disabled state for the NB3W800L low power NMOS Push–Pull outputs is Low/Low.

Please note that the logic level for assertion or deassertion is different in software than it is on hardware. Output is enabled if OE# pin is pulled low and still maintains software programming logic with output enabled if OE register is true.

The assertion and de-assertion of this signal is absolutely asynchronous.

#### OE# Assertion (Transition from '1' to '0')

All differential outputs that were tristated will resume normal operation in a glitch free manner.

#### OE# De-Assertion (Transition from '0' to '1')

Corresponding output will transition from normal operation to tri-state in a glitch free manner.

#### 100M\_133M# - Frequency Selection

The 100M\_133M# is a hardware pin, which programs the appropriate output frequency of the DIF pairs. Note that the CLK\_IN frequency is equal to CLK\_OUT frequency. An external pull-up or pull-down resistor is attached to this pin to select the input/output frequency.

#### PWRGD/PWRDN#

PWRGD/PWRDN# is a dual function pin. PWRGD is asserted high and de-asserted low. De-assertion of PWRGD (pulling the signal low) is equivalent to indicating a powerdown condition. PWRGD (assertion) is used by the NB3W800L to sample initial configurations such as frequency select condition and SA selections.

After PWRGD has been asserted high for the first time, the pin becomes a PWRDN# (Power Down) pin that can be used to shut off all clocks cleanly and instruct the device to invoke power savings mode. PWRDN# is a completely asynchronous active low input. When entering power savings mode, PWRDN# should be asserted low **prior to shutting off the input clock or power** to ensure all clocks shut down in a glitch free manner. When PWRDN# is asserted low by two consecutive rising edges of DIF#, all differential outputs are held tri–stated on the next DIF# high to low transition. The assertion and de-assertion of PWRDN# is absolutely asynchronous.

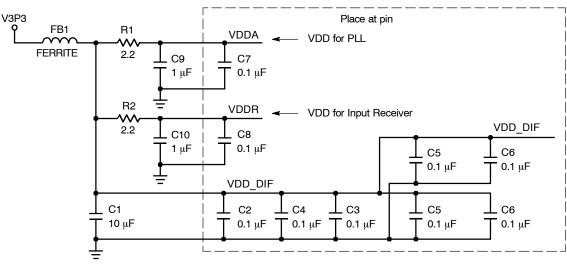
**WARNING:** Disabling of the CLK\_IN input clock prior to assertion of PWRDN# is an undefined mode and not recommended. Operation in this mode may result in glitches, excessive frequency shifting, etc.

#### Table 18. PWRGD/PWRDN# FUNCTIONALITY

PWRGD/PWRDN#	DIF	DIF#
0	Tri-state	Tri-state
1	Running	Running

#### HBW\_BYPASS\_LBW#

The HBW\_BYPASS\_LBW# is a tri level function input pin. It is used to select between PLL high bandwidth, bypass mode and PLL low bandwidth mode.



# POWER FILTERING EXAMPLE

Figure 7. Schematic Example of the NB3W800L Power Filtering

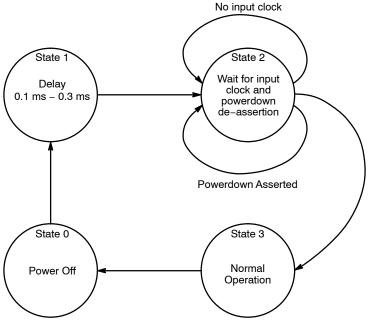
#### Buffer Power–Up State Machine

#### Table 19. BUFFER POWER-UP STATE MACHINE

State	Description
0	3.3 V Buffer power off
1	After 3.3 V supply is detected to rise above 3.135 V, the buffer enters State 1 and initiates a 0.1 ms-0.3 ms delay.
2	Buffer waits for a valid clock on the CLK input and PWRDN# de-assertion (or PWRGD assertion low to high)
3	Once the PLL is locked to the CLK_IN input clock, the buffer enters state 3 and enables outputs for normal operation. (Notes 57, 58)

57. The total power up latency from power on to all outputs active must be less than 1.8 ms (assuming a valid clock is present on CLK\_IN input, 58. If power is valid and powerdown is de-asserted (PWRGD asserted) but no input clocks are present on the CLK IN input, DIF clocks must

remain disabled. Only after valid input clocks are detected, valid power, PWRDN# de-asserted (PWRGD asserted) with the PLL locked/stable and the DIF outputs enabled.



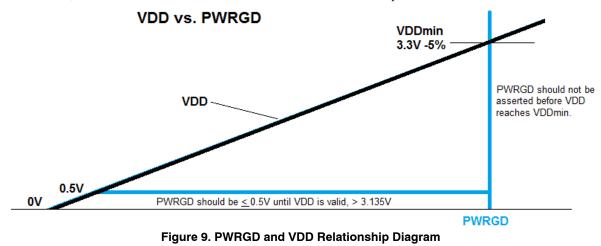
#### Figure 8. Buffer Power–Up State Diagram

#### **Device Power-Up Sequence**

Follow the power–up sequence below for proper device functionality:

- 1. PWRGD/PWRDN# pin must be Low.
- Assign remaining control pins to their required state (100M\_133M#, HBW\_BYPASS\_LBW#, SDA, SCL)
- 3. Apply power to the device.
- Once the VDD pin has reached a valid VDDmin level (3.3V –5%), the PWRGD/PWRDN# pin must be asserted High. See Figure 9.

Note: If no clock is present on the CLK\_IN/CLK\_IN# pins when device is powered up, there will be no clock on DIF/DIF# outputs.





# General SMBus Serial Interface Information for NB3W800L

### How to Write

- Controller (host) sends a start bit
- Controller (host) sends the write address
- Clock(device) will **acknowledge**
- Controller (host) sends the beginning byte location = N
- Clock(device) will acknowledge
- Controller (host) sends the byte count = X
- Clock(device) will acknowledge
- Controller (host) starts sending Byte N through Byte N+X-1
- Clock(device) will **acknowledg**e each byte **one at a time**
- Controller (host) sends a Stop bit

	Index E	Block Write O	peration
Cont	troller (Host)		Clock (Device)
Т	starT bit		
Sla	ve Address		
WR	WRite		
			ACK
Begin	ning Byte = N		
			ACK
Data E	Byte Count = X		
			ACK
Begi	nning Byte N		
			ACK
0			
0		X Byte	0
0			0
			0
Byt	e N + X – 1		
			ACK
Р	stoP bit		

# How to Read

- Controller (host) will send a start bit
- Controller (host) sends the write address
- Clock(device) will acknowledge
- Controller (host) sends the beginning byte location = N
- Clock(device) will acknowledge
- Controller (host) will send a separate start bit
- Controller (host) sends the read address
- Clock(device) will acknowledge
- Clock(device) will send the data byte count = X
- Clock(device) sends Byte N+X-1
- Clock(device) sends Byte 0 through Byte X (if X<sub>(H)</sub> was written to Byte 8)
- Controller (host) will need to acknowledge each byte
- Controller (host) will send a not acknowledge bit
- Controller (host) will send a stop bit

	Index Block Read Operation								
Cor	ntroller (Host)		Clock (Device)						
Т	starT bit								
SI	ave Address								
WR	WRite								
			ACK						
Begi	nning Byte = N								
			ACK						
RT	Repeat starT								
SI	ave Address								
RD	ReaD								
			ACK						
			Data Byte Count = X						
	ACK								
			Beginning Byte N						
	ACK								
		X Byte	0						
	0	,	0						
L	0		0						
L	0								
			Byte N + X - 1						
N	Not acknowledge								
Р	stoP bit								

# Table 20. SMBus TABLE: PLL MODE, AND FREQUENCY SELECT REGISTER

Byte 0	Pin #	Name	Control Function	Туре	0	1	Default		
Bit 7	48	PLL Mode 1	PLL Operating Mode Rd back 1	R	See PLL Operating Mode Readback Table				Latched at power up
Bit 6	48	PLL Mode 0	PLL Operating Mode Rd back 0	R			Latched at p		Latched at power up
Bit 5			Reserved				0		
Bit 4			Reserved						
Bit 3		PLL_SW_EN	Enable S/W control of PLL BW	RW	HW Latch	SMBus Control	0		
Bit 2		PLL Mode 1	PLL Operating Mode 1	RW		erating Mode	1		
Bit 1		PLL Mode 0	PLL Operating Mode 0	RW	Readback Table		1		
Bit 0	47	100M_133M#	Frequency Select Readback	R	133 MHz	100 MHz	Latched at power up		

NOTE: Setting bit 3 to '1' allows the user to overide the Latch value from pin 48 via use of bits 2 and 1. Use the values from the PLL Operating Mode Readback Table. Note that Bits 7 and 6 will keep the value originally latched on pin 48. A warm reset of the system will have to accomplished if the user changes these bits.

# Table 21. SMBus TABLE: OUTPUT CONTROL REGISTER

Byte 1	Pin #	Name	Control Function	Туре	0	1	Default		
Bit 7	32/33	DIF_5_En	Output Control - '0' overrides OE# pin	RW	Low/Low	Enable	1		
Bit 6	28/29	DIF_4_En	Output Control - '0' overrides OE# pin	RW			1		
Bit 5	25/26	DIF_3_En	Output Control - '0' overrides OE# pin	RW			1		
Bit 4	21/22	DIF_2_En	Output Control - '0' overrides OE# pin	RW			1		
Bit 3		Reserved							
Bit 2	16/17	DIF_1_En	Output Control - '0' overrides OE# pin	RW	Low/Low	Enable	1		
Bit 1	13/14	DIF_0_En	Output Control - '0' overrides OE# pin	RW			1		
Bit 0			Reserved				1		

#### Table 22. SMBus TABLE: OUTPUT CONTROL REGISTER

Byte 2	Pin #	Name	Control Function	Туре	0	1	Default		
Bit 7			Reserved						
Bit 6			Reserved						
Bit 5			Reserved						
Bit 4			Reserved						
Bit 3			Reserved						
Bit 2	39/40	DIF_7_En	Output Control - '0' overrides OE# pin	RW	Low/Low	Enable	1		
Bit 1		Reserved							
Bit 0	35/36	DIF_6_En	Output Control - '0' overrides OE# pin	RW	Low/Low	Enable	1		

#### Table 23. SMBus TABLE: RESERVED REGISTER

Byte 3	Pin #	Name	Control Function	Туре	0	1	Default		
Bit 7			Reserved				0		
Bit 6			Reserved						
Bit 5			Reserved						
Bit 4			Reserved						
Bit 3			Reserved						
Bit 2			Reserved				0		
Bit 1			Reserved				0		
Bit 0			Reserved				0		

# Table 24. SMBus TABLE: RESERVED REGISTER

Byte 4	Pin #	Name	Control Function	Туре	0	1	Default		
Bit 7			Reserved				0		
Bit 6			Reserved						
Bit 5			Reserved						
Bit 4			Reserved				0		
Bit 3			Reserved				0		
Bit 2			Reserved				0		
Bit 1			Reserved				0		
Bit 0			Reserved				0		

#### Table 25. SMBus TABLE: VENDOR & REVISION ID REGISTER

Byte 5	Pin #	Name	Control Function	Туре	0	1	Default
Bit 7	-	RID3	REVISION ID	R		0	
Bit 6	-	RID2		R	A rev :	0	
Bit 5	-	RID1		R	A lev :	0	
Bit 4	—	RID0		R		0	
Bit 3	—	VID3		R	-	-	1
Bit 2	—	VID2	VENDOR ID	R	-	-	1
Bit 1	-	VID1	VENDOR ID	R	-	-	1
Bit 0	_	VID0		R	_	-	1

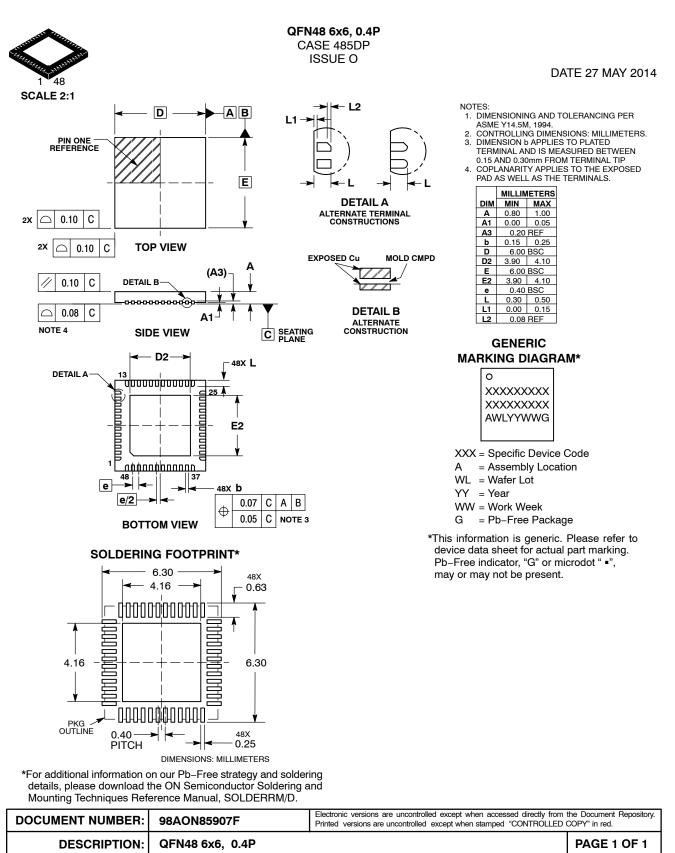
#### Table 26. SMBus TABLE: DEVICE ID

Byte 6	Pin #	Name	Control Function	Туре	0	1	Default
Bit 7	-		Device ID 7 (MSB)	R			1
Bit 6	-	Device ID 6		R			1
Bit 5	-		Device ID 5	R			1
Bit 4	-		Device ID 4	R			0
Bit 3	-	Device ID 3		R			0
Bit 2	-	Device ID 2		R			1
Bit 1	-	Device ID 1		R			1
Bit 0	-		Device ID 0	R			1

#### Table 27. SMBus TABLE: BYTE COUNT REGISTER

Byte 7	Pin #	Name	Control Function	Туре	0	1	Default			
Bit 7		Reserved								
Bit 6			Reserved							
Bit 5			Reserved							
Bit 4	-	BC4		RW	Default value is 8 hex, so 9 bytes (0 to 8) will be read back by default.		0			
Bit 3	-	BC3		RW			1			
Bit 2	-	BC2	Writing to this register configures how many bytes will be read back.	RW			0			
Bit 1	-	BC1		RW			0			
Bit 0	-	BC0		RW		0				





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